



Sheet 1 of 8

Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 124086.03		APPLICATION NO. New U.S. Patent Application 10/775326	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANT(S) Hiroyuki NAGASAKA et al.			
				FILING DATE August 11, 2006		GROUP 2851 1795	

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Examiner Initials	Cite No.	Document Number	Date	Name
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BR	3	2004/0169834 A1	09-02-2004	RICHTER ET AL
BR	4	2004/0169924 A1	09-02-2004	FLAGELLO ET AL
BR	5	2004/0180294 A1	09-16-2004	BABA-ALI ET AL
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BR	13	WO 02/091078 A1	11-14-2002	WIPO	X	X
BR	14	WO 2004/081666 A1	09-23-2004	WIPO	X	X
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				FILING DATE August 11, 2006		GROUP 2891 1795	
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BR	29	WO 2004/092830 A2	10-28-2004	WIPO	X	X	
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INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANT(S) Hiroyuki NAGASAKA et al.			
				FILING DATE August 11, 2006		GROUP 384 1795	
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BR	43	2005/0084794 A1	04-21-2005	MEAGLEY ET AL.			
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BR	47	WO 2005/003864 A2	01-13-2005	WIPO	X	X	
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INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANT(S) Hiroyuki NAGASAKA et al.			
				FILING DATE August 11, 2006		GROUP 985+ 1795	
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BR	66	WO 2005/034174 A2	04-14-2005	WIPO	X	X	
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INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANT(S) Hiroyuki NAGASAKA et al.			
				FILING DATE August 11, 2006		GROUP 3861 <u>1795</u>	
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				FILING DATE August 11, 2006		GROUP 2851 1795	
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BR	91	EP 1 477 856 A1	11-17-2004	EUROPE	X	X	
BR	92	EP 0 834 773 A2	4/8/1998	EUROPE	X	X	
BR	93	WO99/49504	9/30/1999	WIPO	X	X	
BR	94	JP A 62-65326	3/24/1987	JAPAN	X	X	
BR	95	JP A 63-157419	6/30/1988	JAPAN	X	X	
BR	96	JP A 5-304072	11/16/1993	JAPAN	X	X	
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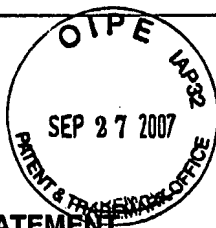
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INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANT(S) Hiroyuki NAGASAKA et al.			
				FILING DATE August 11, 2006		GROUP 3864 1795	
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				FILING DATE August 11, 2006		GROUP 1795 2854 1756	
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BR	121	JP-A-58-202448	11-25-1983	JAPAN	X	—*	
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Date: August 11, 2006



Atty. Dkt. No.	M#	Client Ref.
081468	0308270	P-1812.000-US

**INFORMATION DISCLOSURE STATEMENT
BY APPLICANT**

Applicant: DIERICHS et al.

Appln. No.: 10/775,326

Filing Date: February 11, 2004

Date: September 27, 2007 Page 1 of 4

Examiner: Brittany L. Raymond Group Art Unit: 1756-1795

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BR	AA	Office Action dated January 6, 2006 issued for U.S. Appln. No. 10/898,674			
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BR	CC	Office Action dated August 17, 2006 issued for U.S. Appln. No. 10/898,674			

Examiner: *Brittany Raymond*

Date Considered: *10/9/2007*

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FORM PTO-1449 (modified)
To: U.S. Department of Commerce
(PW FORM PAT-1449)
Patent and Trademark Office

Atty.
Dkt. No.

M#

Client Ref.

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

Applicant: DIERICHS

Appln. No.: 10/775,326

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Examiner: Brittany L. Raymond Group Art Unit: 1756 1795

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BR	VVR	WO 2005/054955 A2	06/2005	PCT		X			
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DDDF									
EEER									

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Applicant: DIERICHS

Appln. No.: 10/775,326

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Examiner: Brittany L. Raymond Group Art Unit: 4756 1795

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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Group Art Unit: 4756 1795

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	RRRRR					
	SSSSR					
	TTTTT					
	UUUUR					

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	WWWW							
	XXXXR							
	YYYYR							
	ZZZZR							
	AAAAA							
	BBBBB							
	CCCCC							
	DDDDD							
	EEEEE							
	FFFFF							
	GGGGG							
	HHHHH							
	IIIIIR							
	JJJJR							
	KKKKK							
	LLLLL							
	MMMMM							

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